

**Search Notes**

Application/Control No.

10/679,290

Examiner

Alex Liew

Applicant(s)/Patent under  
Reexamination

SHISHIDO, CHLE

Art Unit

2624

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
382/141-152,154 limited to text search	3/7/2007	AL
382/141-152,154 limited to text search	9/13/2007	AL